

Market leader for luminescence inspection in the PV industry



PRODUCT CATALOGUE

2019 COLLECTION

LIS-M1

The new benchmark for luminescence inspection of PV modules

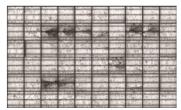
Premium PL imaging tool on full-area PV modules

- Proprietary line scan PL⁺ imaging
- Unique and proprietary series resistance enhanced image analysis
- Exposes module defects not visible in EL images
- Unmatched image quality

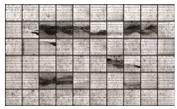


Overview:

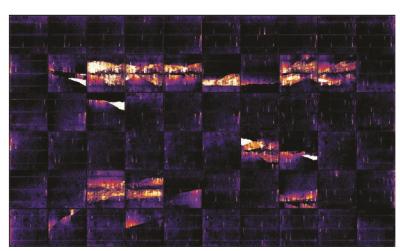
Sample type	✓ Mono and multi Si modules
Specifications of sample	 ✓ Up to 2.2m x 1.2m module size ✓ Supports half-cell and shingle modules ✓ Adaptation to other cell types or materials on request
Technology	✓ Line scan EL and PL imaging
Key applications	✓ Module quality control✓ Module process optimisation
Functions	✓ PL and EL images✓ Resistance-enhanced image
Value propositions	 Proprietary luminescence imaging technique Quantitative degradation analysis Suitable for R&D labs and on the factory floor



PL+ image

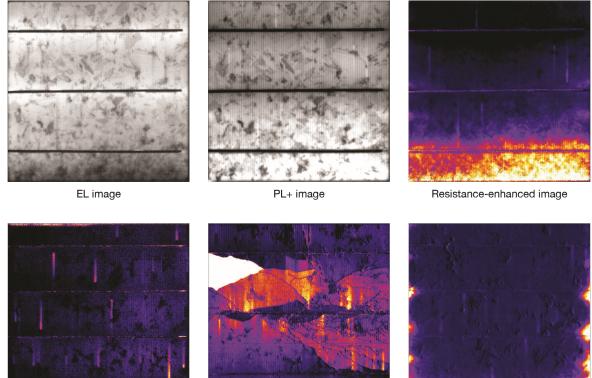


EL image

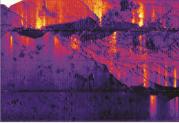


Resistance-enhanced image

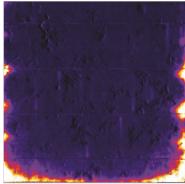
Unambiguous detection of series resistance defects that cannot be classified from EL images:



Cell with broken fingers and edge isolation problems

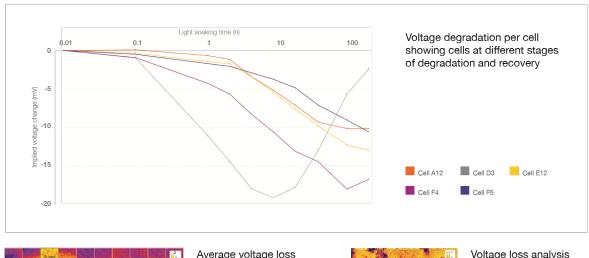


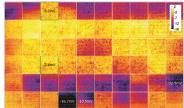
Cell with fully and partially isolated areas due to cracks



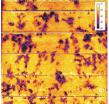
Wide range of resistance or contacting issues detectable

Quantitative loss analysis in degradation studies on fully assembled modules





Average voltage loss analysis on cell level (colour scale shows voltage loss in mV)



Voltage loss analysis showing local variations in degradation dynamics (colour scale shows voltage loss in mV)

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